

**REMARKS**

Claims 1 and 3-6 are pending in this Application. By this Amendment, claims 1, 3 and 6 are amended. Claim 2 is canceled without prejudice to, or disclaimer of, the subject matter recited in that claim. Reconsideration based on the above amendments and the following Remarks is respectfully requested.

Entry of the amendments is proper under 37 C.F.R. §1.116 since the amendments: (a) place the Application in condition for allowance for the reasons discussed below; (b) do not raise any new issue requiring further search and/or consideration since the amendments amplify issues previously discussed throughout prosecution; and (c) place the Application in better form for appeal, should an appeal be necessary. The amendments are necessary and were not earlier presented because they are made in response to arguments raised in the final rejection. Entry of the amendments is thus respectfully requested.

The Office Action, on page 2, rejects claims 1-6 under 35 U.S.C. §103(a) as being unpatentable over Applicant's Admitted Prior Art (APA) Fig. 17 in view of U.S. Patent No. 5,986,739 to Kobayashi. This rejection is respectfully traversed.

To the extent the APA is considered prior art (and Applicant reserves the right to further address this issue later, if necessary and appropriate), Applicant agrees with the Office Action in stating that APA does not teach or suggest the features of a plurality of electrode strips arranged on the protective layer and extending from a formation region of the protective layer to an unformed region of the protective layer, an electrode width of an electrode strip on a step portion forming an outline of the protective layer in the boundary part of the formation region and the unformed region being set to be narrower than an electrode width of an electrode strip on the protective layer in the formation region. The Office Action relies on Kobayashi to overcome this deficiency.

However, Applicant respectfully submits that Kobayashi does not overcome the shortfall of APA. Specifically, in order to accomplish an object of providing a liquid crystal display device, with a high yield in a manufacturing process, and in which a gap between wires is easily measured, without short-circuiting electrodes, the invention of claims 1 and 6 includes a part of an electrode width of an electrode strip within the unformed region of the protective layer being equal to an electrode width of an electrode strip on the protective layer within the formation region and enabling measurement of a gap of the electrodes. This feature is described at, for example, page 12, lines 29-33 of the Specification.

According to this structure, the gap between the strip electrodes in the gap portion of the protective film becomes large. Thus, the possibility of a short-circuit between the strip electrodes in the gap portion can be reduced. At the same time, the electrode width on the non-formation region side of the protective film matches the electrode width on the color material layer, so that the gap between the electrodes can be measured in the non-formation region of the protective film, and the measurement of the gap between the electrodes is not prevented by the reflective light shielding layer.

Applicant respectfully submits that Kobayashi relates to short-circuit and broken wire testing and is thus directed to a different technology area than that which is the subject matter of this Application. Additionally, Applicant respectfully submits that Kobayashi discloses that short-circuit and broken wire testing are performed at the narrow portion of the electrode width, while the subject matter of the current claims describes that the gap between the electrodes is measured at the wide portion of the electrode width. Thus, a completely different electrode portion is of interest according to Kobayashi.

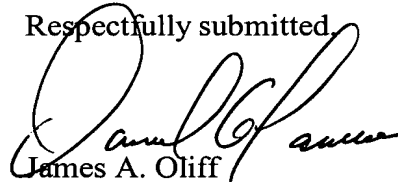
Applicant, therefore, respectfully submits that the combination of the applied references neither discloses nor suggests all of the features recited in independent claims 1 and 6. For at least this reason, claims 1 and 6 would not have been obvious to one of ordinary

skill in the art. Further, Applicant respectfully submits that dependent claims 3-5, though each reciting separately patentable subject matter, include all of the features recited in independent claim 1 from which they directly and indirectly depend and, as such, these claims are likewise neither suggested, nor motivated by, the combination of the applied references. Reconsideration and withdrawal of the rejection of claims 1 and 3-6 under 35 U.S.C. §103(a) as being unpatentable over the combination of the applied references are respectfully requested.

In view of the foregoing, Applicant respectfully submits that this Application is in condition for allowance. Favorable reconsideration and prompt allowance of claims 1 and 3-6 are earnestly solicited.

Should the Examiner believe that anything further would be desirable in order to place this Application in even better condition for allowance, the Examiner is invited to contact Applicant's undersigned representative at the telephone number set forth below.

Respectfully submitted,

  
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Date: May 18, 2004

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